Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/700,094	CHEN ET AL.	
Examiner	Art Unit	
Brian R. Peugh	2187	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
4,154	7/7/2006	BRP			
78.08	7/7/2006	BRP			
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	DATE	EXMR
Updated WEST search (text) IEEE search	7/6/2006	BRP
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